

Integrated intensity of terahertz photoluminescence of doped GaAs epilayers



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In a sample with n-GaAs epitaxial layer, nonequilibrium electrons in the conduction band and holes in the valence band $E \blacktriangle$ are formed under the action of interband optical pumping. Their further thremalization and trapping to impurity levels can be accompanied by emission of THz radiation. Stimulated interband radiation depopulates the main donor (or acceptor) states and can increase the intensity of THz radiation

2. Sample and experimental setup

 $\sim \sim \rightarrow$ \checkmark hv>Eg near IF

Side view GaAs:Si with cavity 0.4x0.4 r lock-in amplifier Pre-amplifier **SR830** SR570 THz > Ge:Ga Sample in a Grating closed cycle cryo monochromator View from above T = 4, 2...320 KHoriba Jobin Yvon FHR-640 Ge:Ga PC Optical windows Optica pumping 532 nm near IR

4. Integrated PL intensity









